

Amendments to the Claims:

This listing of claims replaces all prior versions and listings of claims in this application.

Listing of the Claims:

1. (Currently Amended) A probe module comprising:
a probe base having a plurality of conductive metal traces;
a plurality of probe pins ~~supported by~~ attached to the probe base, each of the probe pins ~~comprises~~ comprising an elongated ~~arm~~ body wherein at least part of the elongated ~~arm~~ body is bonded ~~with~~ to the plurality of conductive metal traces of the probe base; and
a circuit interconnect device for connecting ~~said~~ the plurality of probe pins to an inspection apparatus.
2. (Currently Amended) The probe module of claim 1, wherein each of the plurality of probe pins further comprises a probe pin head ~~supported by~~ extending from the probe pin body and a generally tapered probe pin tip provided on the probe pin head.
3. (Previously Presented) The probe module of claim 1, wherein the circuit interconnect device comprises a plurality of conductive probe circuits provided on the probe base in electrical contact with the plurality of probe pins, respectively, and a flexible circuit board provided in electrical contact with the plurality of conductive probe circuits.
4. (Canceled)
5. (Currently Amended) The probe module of claim 1, wherein each of the plurality of probe pins further comprises a probe pin head ~~supported by~~ extending from the probe pin body and a generally semi-spherical probe pin tip provided on the probe pin head.
6. (Canceled)

7. (Currently Amended) The probe module of claim 1, further comprising a compression arm ~~supported by~~ attached to the probe base and configured to engage the plurality of probe pins.

8-12. (Canceled)

13. (Currently Amended) A probe module ~~comprising:~~ of claim 1 wherein the
a probe base;

[[a]] plurality of probe pins each having an elongated arm portion and have a generally tetrahedral probe pin tip, wherein at least a portion of the elongated arm portion is bonded with the probe base; and

a circuit interconnect device for connecting said plurality of probe pins to an inspection apparatus.

14-17. (Canceled)

18. (Currently Amended) A probe pin for a probe module having a probe base, comprising:
a probe pin body that is elongated and ~~having~~ has at least a portion bonded ~~with to~~ a
conductive metal trace of [[a]] the probe base unit;

a probe pin head ~~supported by~~ extending from the probe bin body; and

a probe pin tip provided on the probe pin head.

19. (Previously Presented) The probe pin of claim 18, wherein the probe pin tip has a generally polyhedral configuration.

20. (Previously Presented) The probe pin of claim 18, wherein the probe pin tip has a generally semi-spherical configuration.

21. (Currently Amended) A probe module comprising:

a probe base having a plurality of conductive metal traces, the probe base being defined by a first end and a second end;

a plurality of probe pins ~~coupled with conductive metal traces~~ electrically connected to the conductive metal traces of the first end of the probe base; and

a flexible circuit board ~~coupling the probe pins for testing~~ electrically connected to the conductive metal traces of the second end of the probe base, thereby allowing the plurality of probe pins to be electrically connected to the flexible circuit board via the plurality of conductive metal traces.

22. (Previously Presented) The probe module of claim 1, wherein the flexible circuit board couples the probe pins to a testing unit via the conductive metal traces.

23. (Previously Presented) The probe module of claim 1, further comprising:
a compression arm configured to engage the probe pins.

24. (Previously Presented) The probe module of claim 1, wherein the probe pins include a probe head having at least one of a tapered, semi-spherical, inverted-pyramid or a tetrahedral shape.

25. (Previously Presented) The probe module of claim 1, wherein the probe pins include an elongated arm body such that at least a part of the elongated arm body is attached with the probe base.

26-32. (Canceled)

33. (New) The probe module of claim 21 wherein the plurality of probe pins are electrically connected to the conductive metal traces of the first end of the probe base by being bonded to the probe base, and the flexible circuit board is electrically connected to the conductive metal traces of the second end of the probe base by being bonded to the probe base.

34. (New) The probe module of claim 7, further comprising at least one adjustment screw provided on the probe base that can be manipulated to adjust the compression arm against the plurality of probe pins to adjust the contact angle of the probe pins.